

Supporting Information For

Tuning the nonlinear susceptibility and linear parameters upon annealing the $\text{Ag}_{60-x}\text{Se}_{40}\text{Te}_x$ nanostructured films for nonlinear and photonic applications

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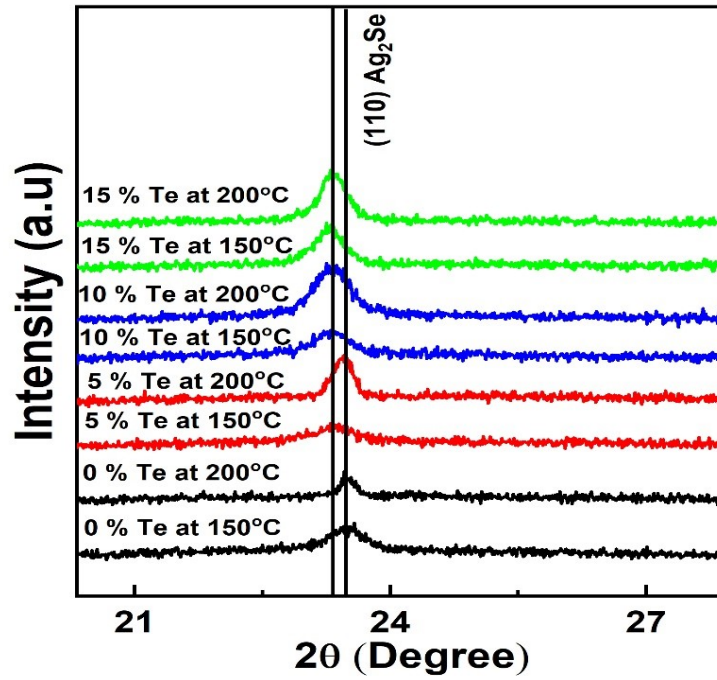


Figure. S1. The XRD pattern of 110 planes (enlarged) to show the peak shifting that corresponds to lattice shifting of the crystalline material.

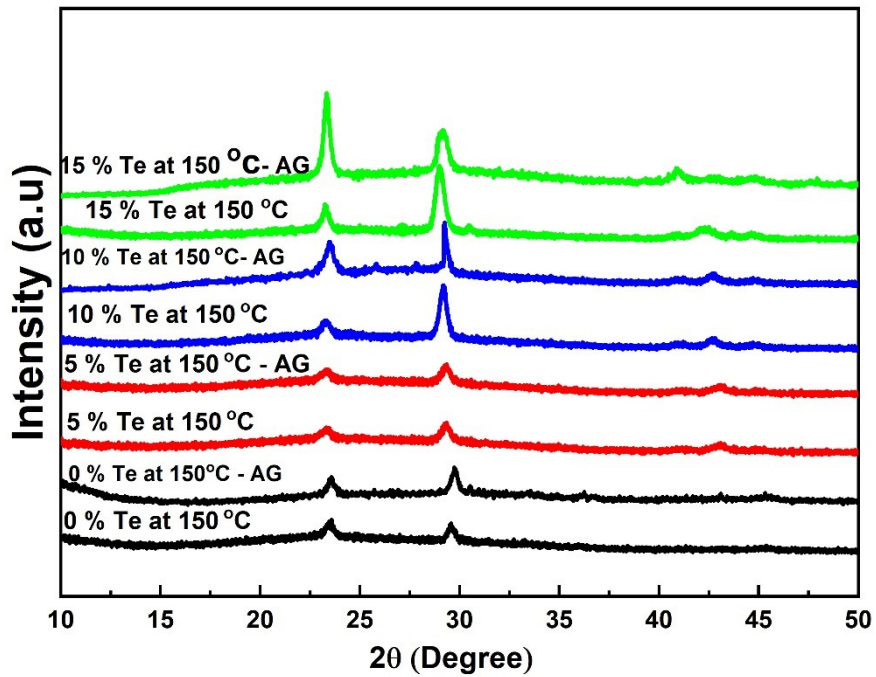


Figure. S2. The XRD pattern of 150 °C annealed $\text{Ag}_{60-x}\text{Se}_{40}\text{Te}_x$ thin films (Previous data and AG- after aging, the recent data)